Silicon N-channel IGBT 3300V F version

FEATURES

- * Soft switching behavior, low switching loss & low conduction loss :
 - Soft low-injection punch-through
 - Advanced Trench High conductivity IGBT.
- \ast Low driving power due to low input capacitance with trench MOS gate.
- * Low noise recovery: Ultra soft fast recovery diode.
- * High Current rate Package.
- \ast Low $R_{th(j\text{-}c)}$ & low stray inductance.
- * RoHS
- * High thermal fatigue durability: (delta Tc=70K, N>30,000cycles)

ABSOLUTE MAXIMUM RATINGS (T_C=25°C)

Item		Symbol	Unit	MBN1200F33F
Collector Emitter Voltage		V _{CES}	V	3,300
Gate Emitter Voltage		V _{GES}	V	±20
Collector Current	DC	lc	٨	1,200
	1ms	I _{CRM}	- A	2,400
Forward Current	DC	IF	- A	1,200
	1ms	I _{FRM}	A	2,400
Junction Temperature		T _{vj op}	°C	-50 ~ +150
Storage Temperature		T _{stg}	°C	-55 ~ +150
Isolation Voltage		V _{ISO}	V _{RMS}	6,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	- N·m	2/15 (1)
	Mounting (M6)	-		6 (2)

Notes: (1) Recommended Value 1.8±0.2/15⁺⁰-3N·m (2) Recommended Value 5.5±0.5N·m

ELECTRICAL CHARACTERISTICS

ltem	Symbol	Unit	Min.	Тур.	Max.	Test Conditions
Collector Emitter Cut-Off Current	ICES	mA	-	-	0.4	V _{CE} =3,300V, V _{GE} =0V, T _{vj} =25°C
	ICES		-	25	65	V _{CE} =3,300V, V _{GE} =0V, T _{vj} =150°C
Gate Emitter Leakage Current	IGES	nA	-500	-	+500	$V_{GE}=\pm 20V, V_{CE}=0V, T_{vj}=25^{\circ}C$
Collector Emitter Saturation Voltage	V _{CEsat}	V	2.5	2.85	3.5	I _C =1,200A, V _{GE} =15V, T _{vj} =150°C
Gate Emitter Threshold Voltage	V _{GE(th)}	V	5.5	6.5	7.5	V _{CE} =10V, I _C =1,200mA, T _{vj} =25°C
Input Capacitance	Cies	nF	-	88	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C
Internal Gate Resistance	R _{G(int)}	Ω	-	1.9	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C
Turn On Delay Time	t _{d(on)}	μS	0.7	1.0	1.3	V _{CC} =1,800V, I _C =1,200A
Rise Time	tr		0.1	0.2	0.3	L _S =100nH
Turn Off Delay Time	t _{d(off)}		1.7	2.7	3.3	$R_{G}(\text{on/off})=6.8\Omega/8.2\Omega (3)$
Fall Time	t _f		1.0	1.8	2.6	V _{GE} =±15V, T _{vj} =150°C
Peak Forward Voltage Drop	VF	V	2.2	2.6	2.9	I _F =1,200A, V _{GE} =0V, T _{vj} =150°C
Reverse Recovery Time	t _{rr}	μS	0.2	0.7	1.1	V _{CC} =1,800V, I _F =1,200A, L _S =100nH
						T _{vi} =150°C
Turn On Loss	Eon	J/P	-	2.6	3.4	V _{CC} =1,800V, I _C =1,200A, L _S =100nH
Turn Off Loss	E _{off}	J/P	-	2.2	2.7	$R_{G}(\text{on/off})=6.8\Omega/8.2\Omega (3)$
Reverse Recovery Loss	Err	J/P	-	1.7	2.2	V _{GE} =±15V, T _{vi} =150°C
Short Circuit Pulse Width	+	μS	10	-	-	V _{CC} =2,000V, Ls=100nH
Short Circuit Fuise Width	t _{sc}					$R_{G}(on/off)=6.8/82\Omega, V_{GF}=\pm 15V, T_{vj}=150^{\circ}C$
Stray inductance module	L _{SCE}	nH	-	10	-	
Thermal Impedance	R _{th(j-c)}	K/W	-	-	0.010	Junction to case
FVVD	R _{th(j-c)}		-	-	0.017	
Contact Thermal Impedance	R _{th(c-f})	K/W	-	0.008	-	Case to fin

Notes: (3) R_{G} value is a test condition value for evaluation, not recommended value.

Please, determine the suitable R_G value by measuring switching behaviors.

* Please contact our representatives at order.

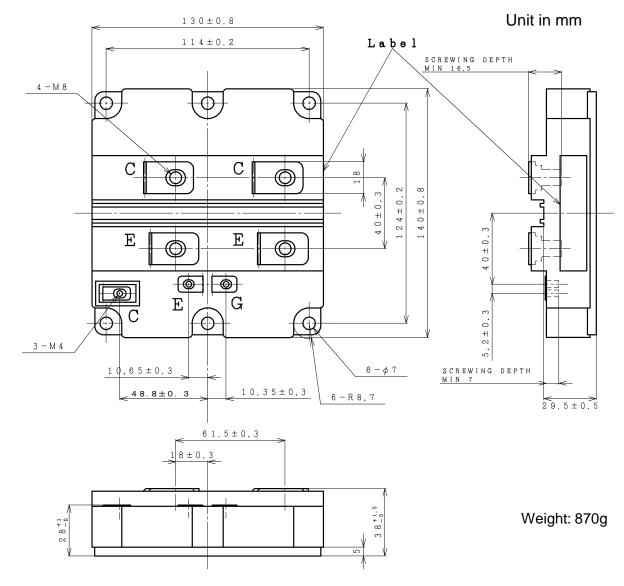
* For improvement, specifications are subject to change without notice.

* For actual application, please confirm this spec sheet is the newest revision.

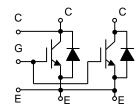
* ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.



OUTLINE DRAWING



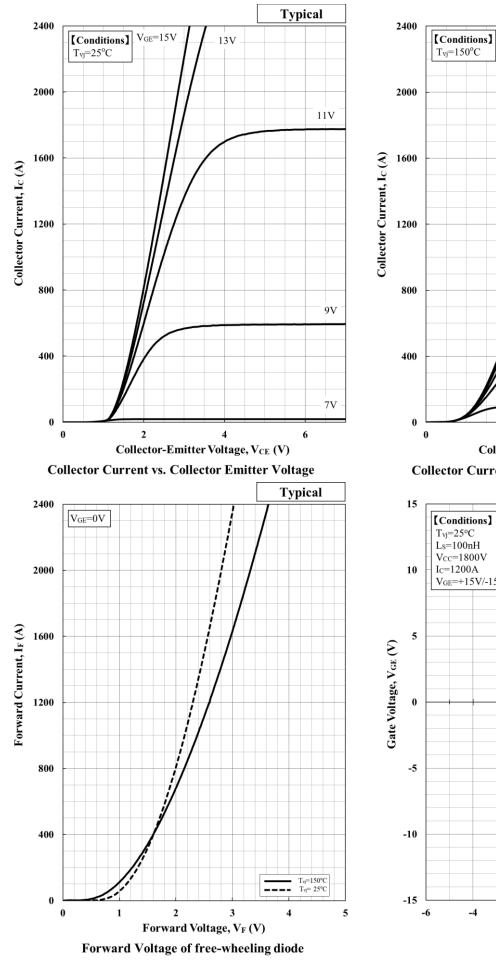
CIRCUIT DIAGRAM

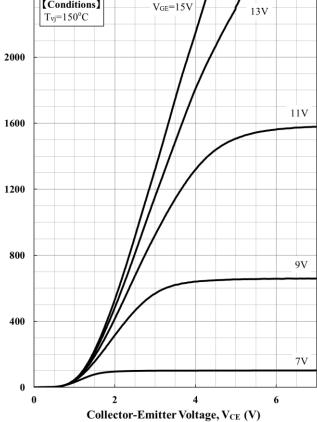




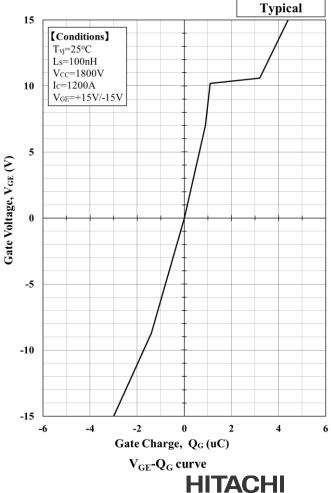
Typical

MBN1200F33F

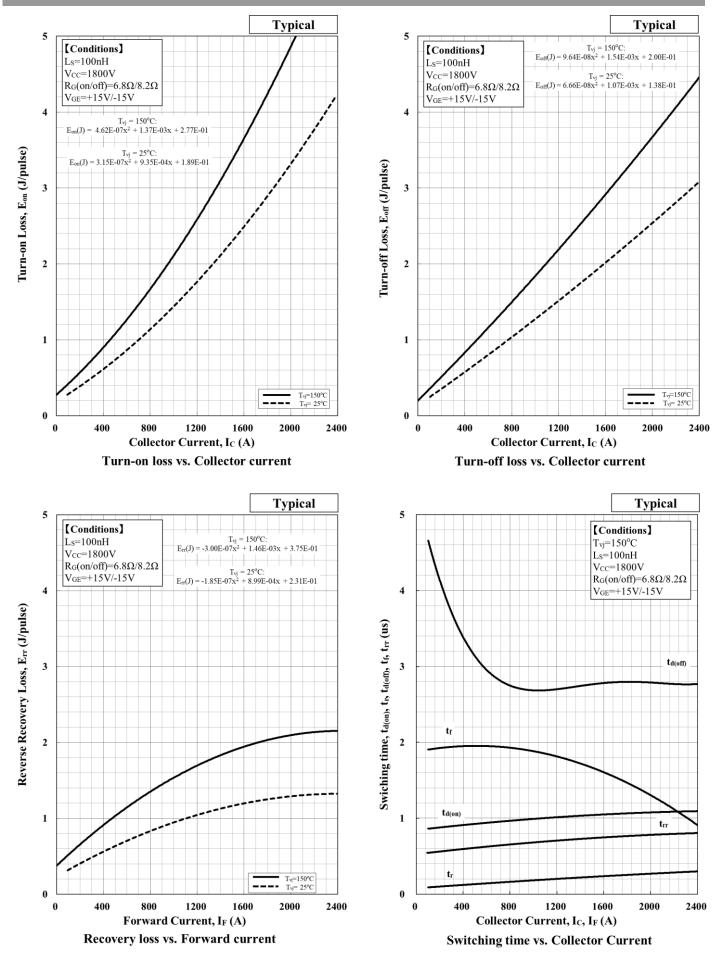




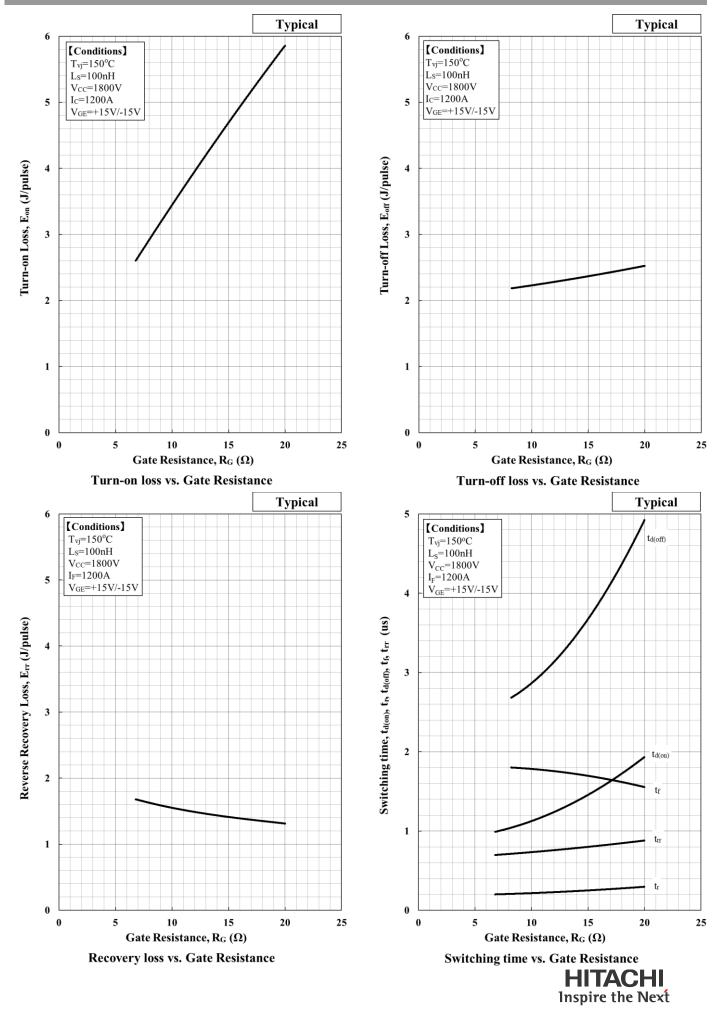
Collector Current vs. Collector Emitter Voltage



Inspire the Next





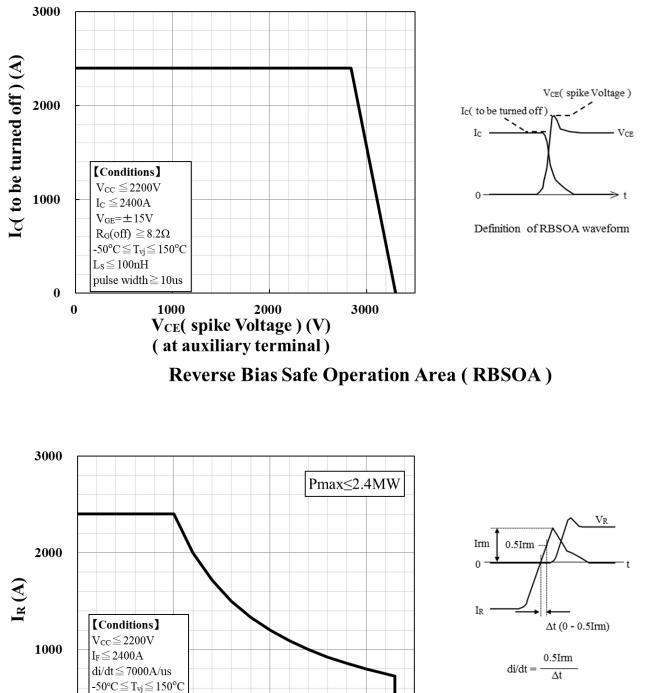


 $L_s \leq 100 nH$ Pulse width $\geq 10 us$

1000

0

0



Definition of Recovery di/dt

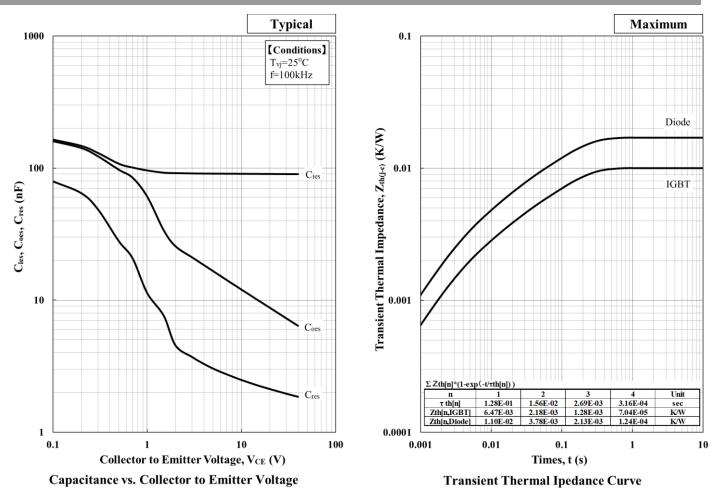
Reverse Recovery Safe Operation Area (RRSOA)

3000

2000

V_R (V) (at auxiliary terminal)







HITACHI POWER SEMICONDUCTORS

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